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Guohai Situ
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Introduction

This volume contains the papers presented during The 2017 International Conference on Optical Instrument and Technology (OIT 2017) at the topical meeting Optoelectronic Imaging/Spectroscopy and Signal Processing Technology.

The focus of this meeting was especially directed to the advances in this field and related areas. The extended scope was honored by a great response to our call for papers. Scientists and engineers, in particular from China, offered more than 90 submitted abstracts. This enormous response demanded a strong review of the abstracts to select the best out of the overwhelming number of excellent submissions. The strong limitation of the number of papers which can be presented orally and discussed effectively during a one-and-a-half day meeting without holding parallel sessions was again an important orientation. The classification of all accepted presentations into the topical sessions was also very difficult and often required compromises. We hope that our decision will be accepted by the audience.

The editors would like to express their thanks to the international program committee for helping us to find a good solution to finalize the meeting. We would also like to thank all the authors who spent much time and effort in the preparation of their papers. Our appreciation would also go to Professor Yunan Sun and Mrs. Cuiling Li, and all the local staff from Beijing Institute of Technology (China). Without their help, it was not possible to make the meeting so successful.

Guohai Situ
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